



Inventor: Werner Juengling et al.

Title: Methods of Forming Materials Between Conductive Electrical Components, and Insulating Materials

Assignee: Micron Technology, Inc.

**INFORMATION DISCLOSURE STATEMENT**

References – See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully submitted,

Dated:

*January 26, 2004*

By:

*Jennifer J. Taylor*

Jennifer J. Taylor, Ph.D.

Reg. No. 48,711

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1789	SERIAL NO. 09/976,624
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 2px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">O I P E</div> <div style="position: absolute; bottom: 0; right: 0; width: 100px; height: 100px; border: 2px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; font-weight: bold;">JAN 26 2004</div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)	
				APPLICANT Werner Juengling et al.	
				FILING DATE October 12, 2001	GROUP 2813

  

U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,039,847	03-2000	Chayahara et al.		
	AB	4,572,848	02-1986	Pollak et al.		
	AC	5,380,511	01-1995	Arahoru et al.		
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*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
	AP						
	AQ						

  

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
AR		Gayet, et al., Translation of EP 0923125 A1, "Process For Making Metal Interconnections In Integrated Circuits" 6/1999
AS		Wolf, et al. Silicon Processing for the VLSI Era, Vol. 1-Process Technology, Lattice Press: Sunset Beach CA, 1986, pp. 428-429.
AT		

  

EXAMINER	DATE CONSIDERED
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-159 <div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block; transform: rotate(-45deg);">           OFFICE            JAN 26 2004            U.S. DEPT. OF COMMERCE            PATENT &amp; TRADEMARK OFFICE         </div>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1789		SERIAL NO. 09/976,624	
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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AB	6,271,146 B1	08-2001	Ross				
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